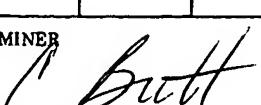
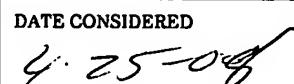


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OTHER DOCUMENTS <small>(Including Author, Title, Date, Pertinent Pages, Etc.)</small>			
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